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<b>Application Number</b>	10/086,025
<b>Filing Date</b>	February 28, 2002
<b>First Named Inventor</b>	Marc R. Anderson
<b>Group Art Unit</b>	1743
<b>Examiner Name</b>	
<b>Attorney Docket Number</b>	286697-00005

Sheet	1	of	1	Attorney Docket Number	286697-00005
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6-25-03

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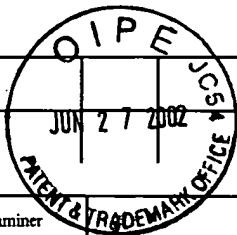
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<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>  (use as many sheets as necessary)				<b>Complete if Known</b>	
				Application Number	10/086,025
				Filing Date	February 28, 2002
				First Named Inventor	Marcus Anderson
				Group Art Unit	1743
				Examiner Name	
Sheet	1	of	1	Attorney Docket Number	286697-0005

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* AS		FASSETT et al., <i>Determination of Nanogram Quantities of Vanadium in Biological Material by Isotope Dilution Thermal Ionization Mass Spectrometry with Ion Counting Detection</i> , Anal. Chem. (November 1985), pp. 2474-2478, V57, No. 13.	
* AS		FASSETT et al., <i>Isotope Dilution Mass Spectrometry for Accurate Elemental Analysis</i> , Anal. Chem. (May 15, 1989), pp. 643A-649A V61, No. 10.	
AS		VIEZMAN et al., <i>On-line Isotope Dilution and Sample Dilution by Flow Injection and Inductively Coupled Plasma Mass Spectrometry</i> , J. Anal. Atom. Spectro. (April 1990), pp. 125-133, V5.	
AS		ROTTMANN et al., <i>Determination of Heavy Metal Interactions with Dissolved Organic Materials in Natural Aquatic Systems by Coupling a High-Performance Liquid Chromatography System with an Inductively Coupled Plasma Mass Spectrometer</i> , Anal. Chem. (November 1, 1994), pp. 3709-3715, V66.	
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AS		COLE, <i>Electrospray Ionization Mass Spectrometry: Fundamentals, Instrumentation and Applications</i> , John Wiley & Sons, Inc. (1997), New York.	
AS		STEWART, <i>Electrospray mass spectrometry: a tool for elemental speciation</i> , Spectrochimica, Acta. (1999), pp. 1649-1695, Part-B, Vol. 54.	
* AS		<i>International Technology Roadmap for Semiconductors 1999 Edition: Defect Reduction</i> , Sematech, Austin, TX, pp. 269-293.	
AS		NEWTON et al., <i>Analysis of Copper Plating Baths - Suppressors and Levelers</i> , Electrochemical Society Proceedings, pp. 1-5, V2000-27.	

Anders Soderquist 6/25/03



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